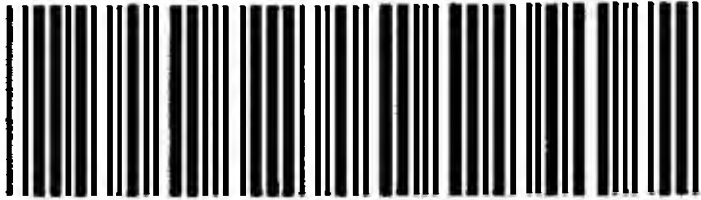


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/710,016	CHUANG ET AL.	
	Examiner	Art Unit	
	Gopal C. Ray	2111	

SEARCHED			
Class	Subclass	Date	Examiner
710	305,33,74,1,315,316	9/26/2005	GCR
709	228,230	9/26/2005	GCR
709	250	9/26/2005	GCR
711	149,100	9/26/2005	GCR
711	145,211	9/26/2005	GCR
713	1,100	9/26/2005	GCR
704	7	9/26/2005	GCR
365	63,189.08	9/26/2005	GCR
365	230.03	9/26/2005	GCR
365	230.05	9/26/2005	GCR

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
WEST: USPT, US OCR, EPO ABS, JPO ABS, DWPI, IBM TDB (sse search history printouts)	9/22/2005	GCR
EAST: USPT (sse search history printouts)	9/22/2005	GCR
NPL: IEEE Xplore (sse search history printouts)	9/22/2005	GCR